

<b>Notice of References Cited</b>	Application/Control No. 10/796,290	Applicant(s)/Patent Under Reexamination NAKAMURA ET AL.	
	Examiner Pedro J. Cuevas	Art Unit 2834	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,788,027 B2	09-2004	Malik, Manfred	320/134
*	B	US-6,326,756 B1	12-2001	Youn, Jeong-Chae	318/569
*	C	US-6,315,381 B1	11-2001	Wade et al.	347/19
*	D	US-6,043,995 A	03-2000	Leuthen, John Michael	363/37
*	E	US-5,526,448 A	06-1996	Nagata et al.	385/1
*	F	US-5,167,660 A	12-1992	Altendorf, Hans-Walter	606/40
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 2004095350 A2	11-2004	World Intellect	BRIDGELALL, RAJ	G06K 0/
	O	JP 2003324735 A	11-2003	Japan	YOSHIMOTO et al.	H04N 07/24
	P	JP 11121145 A	04-1999	Japan	KANEKO et al.	H05B 03/00
	Q	JP 10301983 A	11-1998	Japan	MIYAZAWA, TAMAMI	G06F 17/50
	R	JP 10051945 A	02-1998	Japan	YASHIMA et al.	H02H 03/34
	S	JP 62274175 A	11-1987	Japan	IKEDA et al.	F16K 31/06
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.